

BS EN 62418:2010



BSI Standards Publication

Semiconductor devices — Metallization stress void test

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National foreword

This British Standard is the UK implementation of EN 62418:2010. It is identical to IEC 62418:2010.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

This publication does not purport to include all the necessary provisions of a contract. Users are responsible for its correct application.

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ISBN 978 0 580 62610 4

ICS 31.080.01

Compliance with a British Standard cannot confer immunity from legal obligations.

This British Standard was published under the authority of the Standards Policy and Strategy Committee on 31 August 2010.

Amendments issued since publication

Amd. No.	Date	Text affected
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